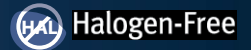


## EPC8004 – Enhancement Mode Power Transistor

 $V_{DS}$ , 40 V $R_{DS(on)}$ , 110 m $\Omega$  $I_D$ , 4 A

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

## Maximum Ratings

PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	40	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 125°C)	48	
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 39^\circ\text{C/W}$ )	4	A
	Pulsed (25°C, $T_{PULSE} = 300 \mu\text{s}$ )	7.5	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	°C
$T_{STG}$	Storage Temperature	-40 to 150	

## Thermal Characteristics

PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	8.2	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	16	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	82	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details

Static Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 125 \mu\text{A}$	40			V
$I_{DSS}$	Drain-Source Leakage	$V_{DS} = 32 \text{ V}$ , $V_{GS} = 0 \text{ V}$		50	100	$\mu\text{A}$
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		100	500	$\mu\text{A}$
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		50	100	
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 0.25 \text{ mA}$	0.8	1.4	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 0.5 \text{ A}$		80	110	m $\Omega$
$V_{SD}$	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$		2.2		V

Specifications are with substrate connected to source where applicable.



EPC8004 eGaN FETs are supplied only in passivated die form with solder bars  
Die Size: 2.1 mm x 0.85 mm

## Applications

- Ultra High Speed DC-DC Conversion
- RF Envelope Tracking
- Wireless Power Transfer
- Game Console and Industrial Movement Sensing (Lidar)

## Benefits

- Ultra High Efficiency
- Ultra Low  $R_{DS(on)}$
- Ultra Low  $Q_G$
- Ultra Small Footprint

Dynamic Characteristics ( $T_j = 25^\circ\text{C}$  unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_{ISS}$	Input Capacitance	$V_{GS} = 0\text{ V}, V_{DS} = 20\text{ V}$		45	52	pF
$C_{OSS}$	Output Capacitance			23	34	
$C_{RSS}$	Reverse Transfer Capacitance			0.8	1.3	
$R_G$	Gate Resistance			0.34		$\Omega$
$Q_G$	Total Gate Charge	$V_{DS} = 20\text{ V}, V_{GS} = 5\text{ V}, I_D = 1\text{ A}$		370	450	pC
$Q_{GS}$	Gate-to-Source Charge			120		
$Q_{GD}$	Gate-to-Drain Charge			47	80	
$Q_{G(TH)}$	Gate Charge at Threshold			95		
$Q_{OSS}$	Output Charge	$V_{GS} = 0\text{ V}, V_{DS} = 20\text{ V}$		630	940	
$Q_{RR}$	Source-Drain Recovery Charge			0		

Specifications are with substrate connected to source where applicable.

Figure 1: Typical Output Characteristics at  $25^\circ\text{C}$

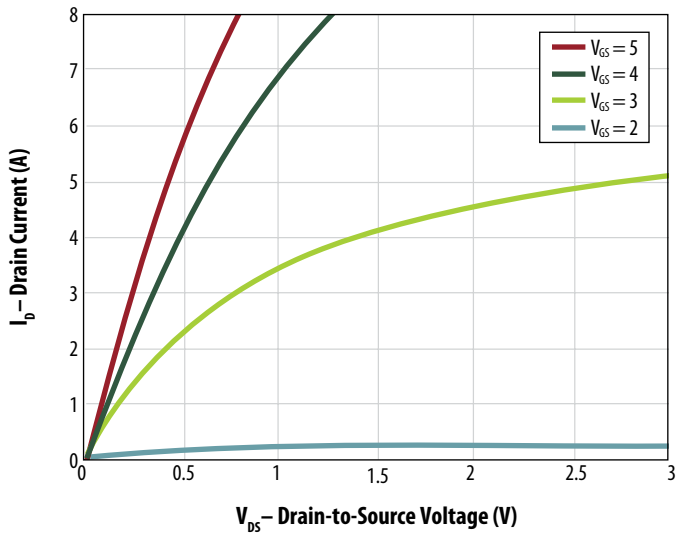


Figure 2: Transfer Characteristics

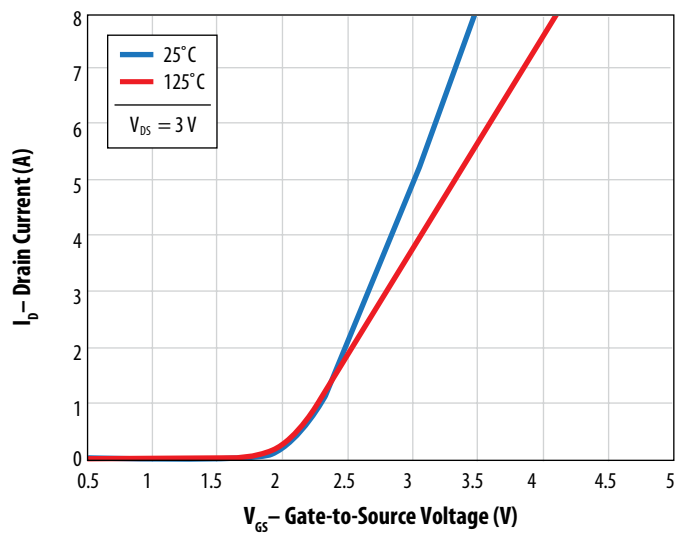


Figure 3:  $R_{DS(ON)}$  vs  $V_{GS}$  for Various Drain Currents

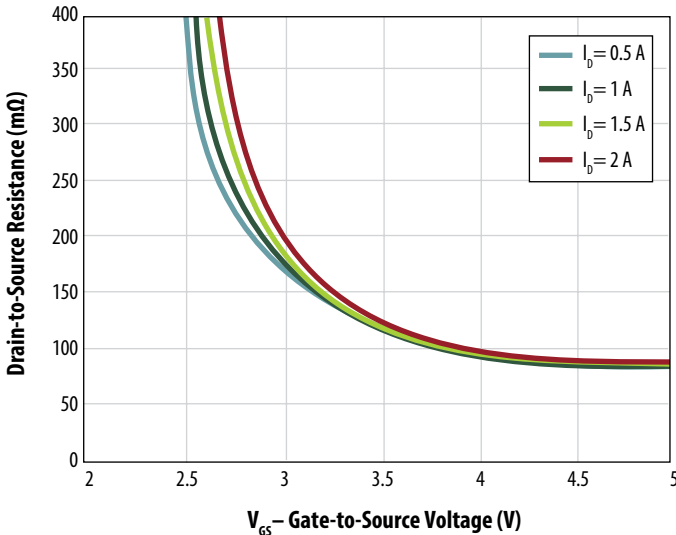


Figure 4:  $R_{DS(ON)}$  vs  $V_{GS}$  for Various Temperatures

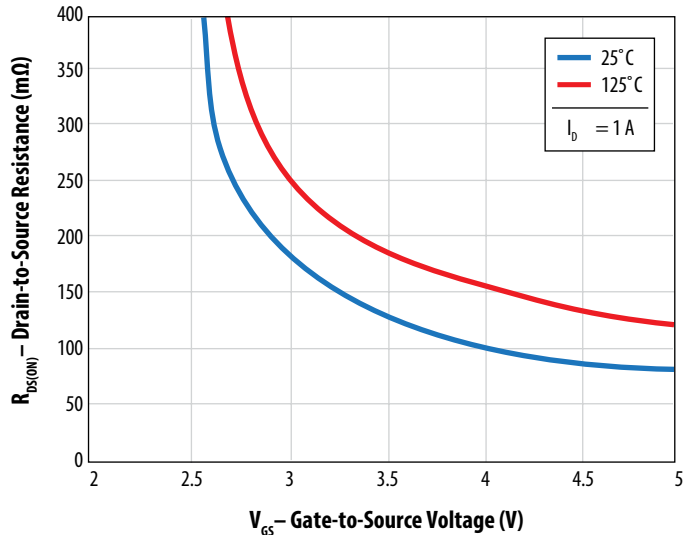


Figure 5: Capacitance (Linear Scale)

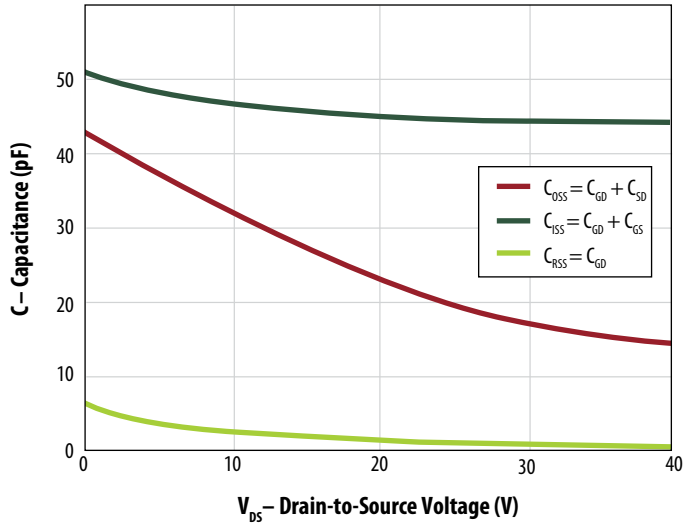


Figure 5A: Capacitance (Log Scale)

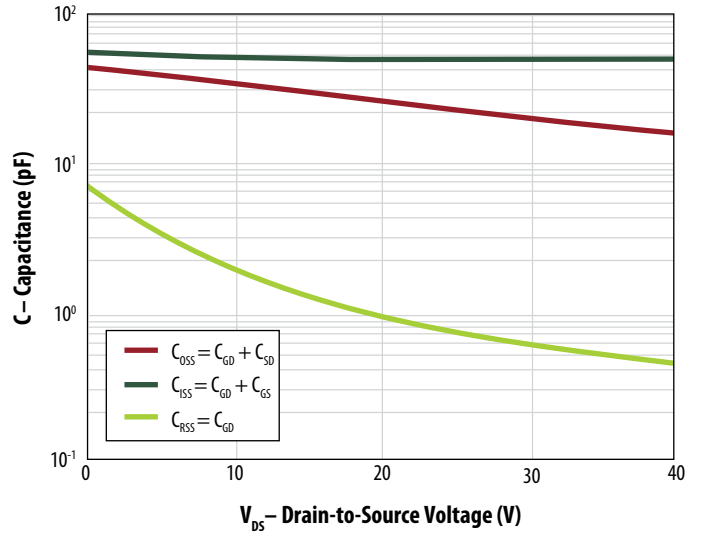


Figure 6: Gate Charge

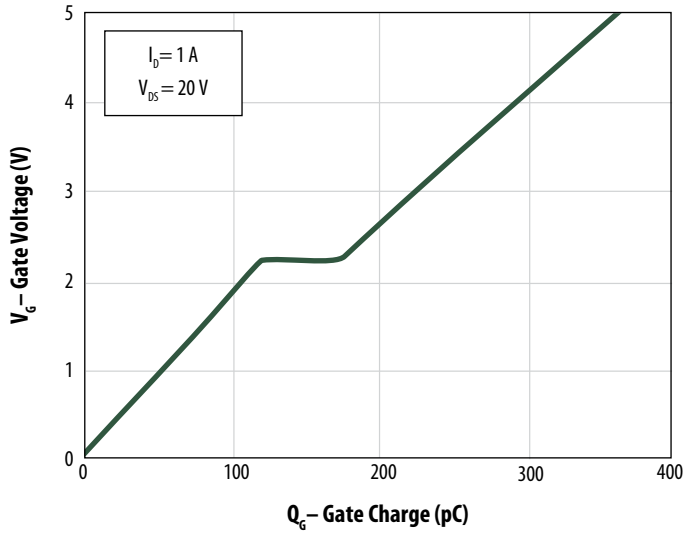


Figure 7: Reverse Drain-Source Characteristics

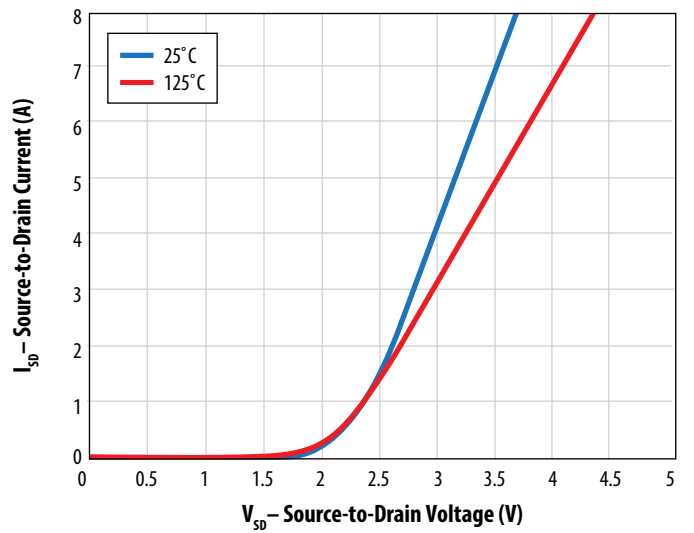


Figure 8: Normalized On Resistance vs Temperature

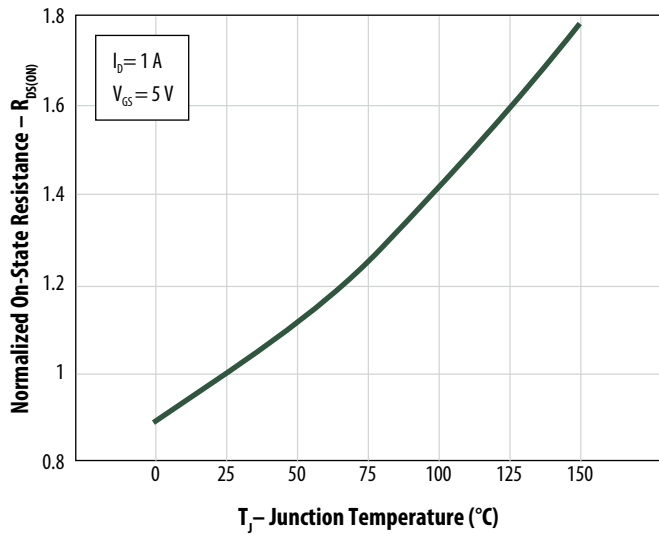


Figure 9: Normalized Threshold Voltage vs Temperature

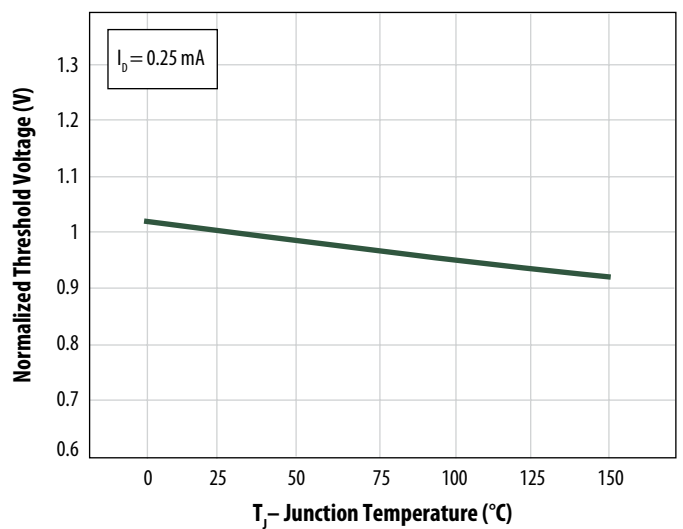
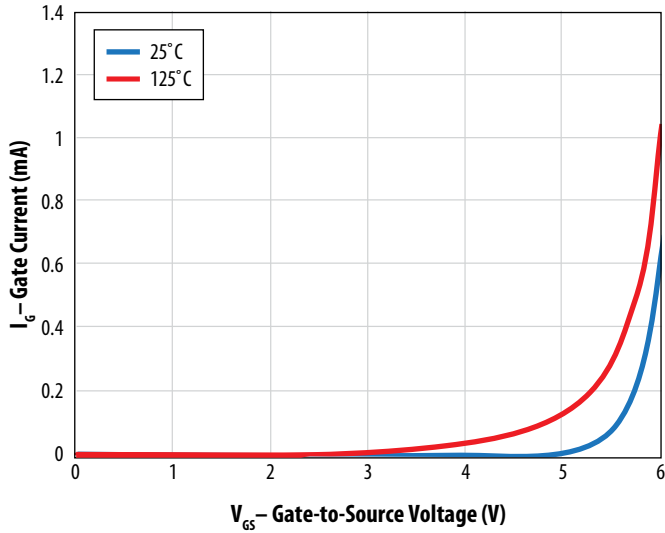
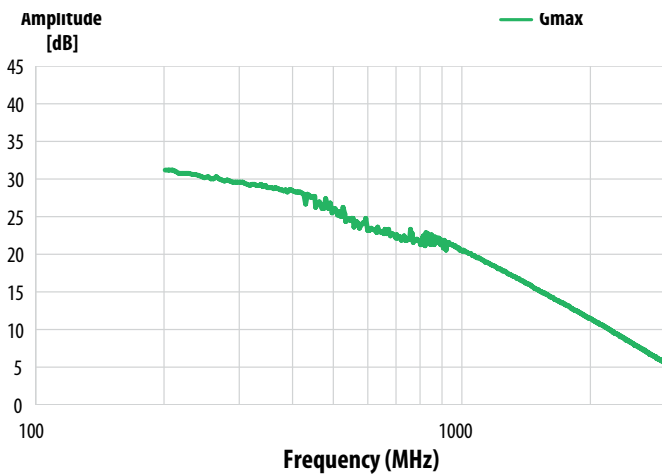


Figure 10: Gate Current



All measurements were done with substrate shortened to source.

Figure 12: Gain Chart



Frequency [MHz]	Gate ( $Z_{GS}$ ) [ $\Omega$ ]	Drain ( $Z_{DS}$ ) [ $\Omega$ ]
200	2.00 - j8.07	15.27 - j6.36
500	1.74 - j2.18	10.78 - j7.01
1000	1.41 + j1.60	5.98 - j4.42
1200	1.30 + j3.20	4.52 - j3.07
1500	1.11 + j4.75	3.19 - j0.98
2000	0.84 + j8.32	2.14 + j3.07
2400	0.70 + j10.24	1.95 + j5.86
3000	0.65 + j14.17	2.17 + j10.24

S-Parameter Table - Download S-parameter files at [www.epc-co.com](http://www.epc-co.com)

Figure 11: Smith Chart

S-Parameter Characteristics  
 $V_{GSQ} = 1.38\text{ V}$ ,  $V_{DSQ} = 20\text{ V}$ ,  $I_{DQ} = 0.50\text{ A}$   
 Pulsed Measurement, Heat-Sink Installed,  $Z_0 = 50\ \Omega$

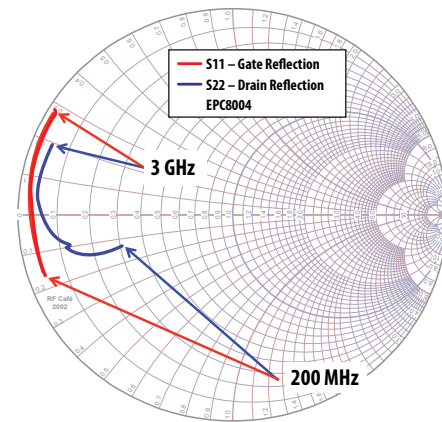


Figure 13: Device Reflection

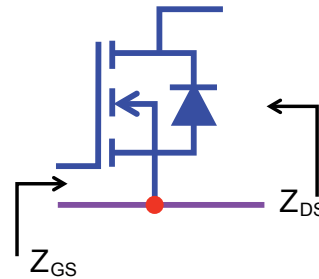


Figure 14: Taper and Reference Plane details – Device Connection

Micro-Strip design: 2-layer  
 1/2 oz (17.5  $\mu\text{m}$ ) thick copper  
 30 mil thick R04350 substrate

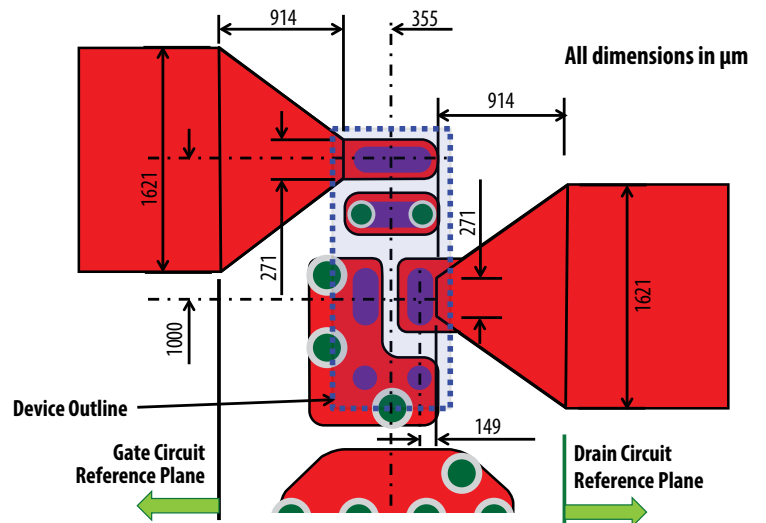


Figure 15: Transient Thermal Response Curves

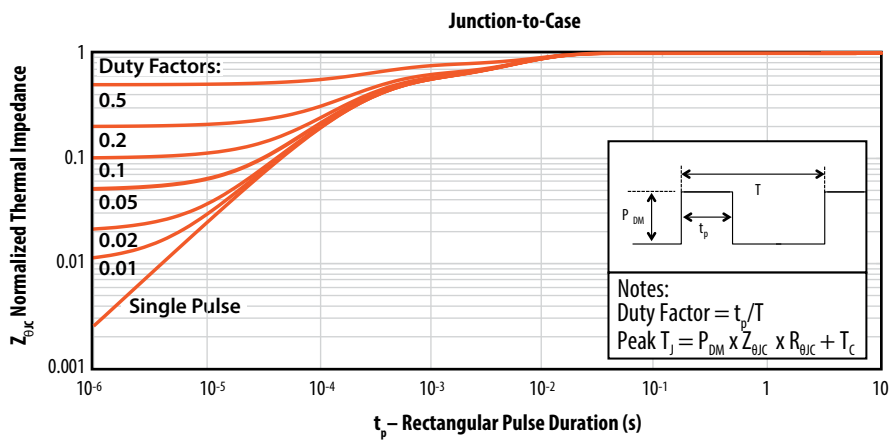
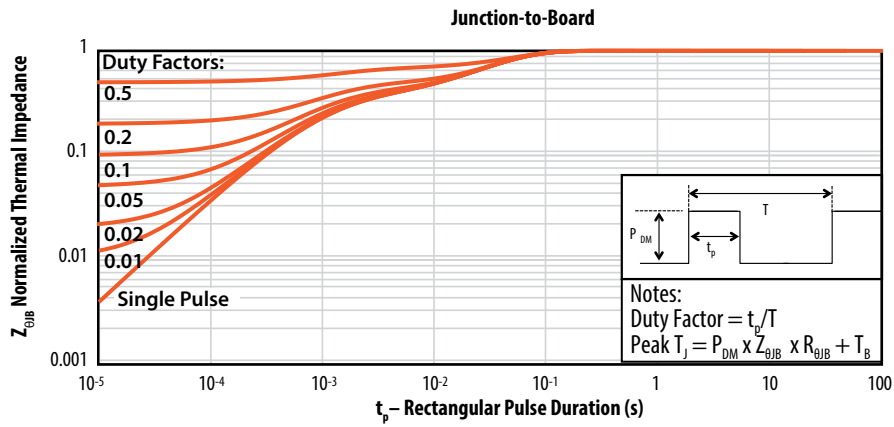
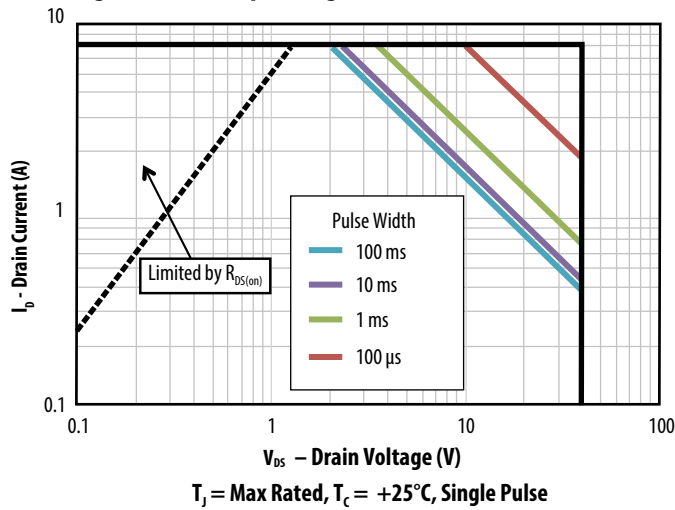
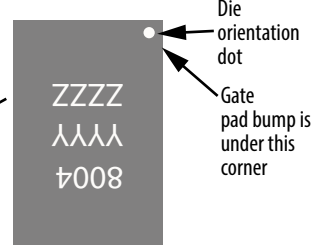
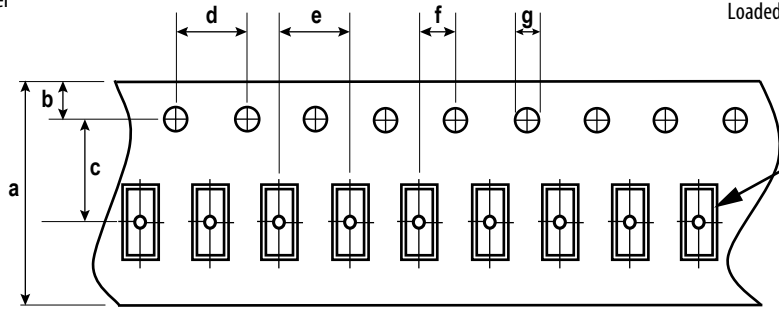
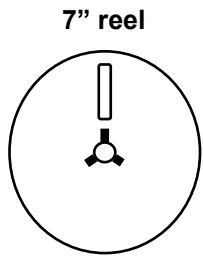


Figure 16: Safe Operating Area



**TAPE AND REEL CONFIGURATION**

4mm pitch, 8mm wide tape on 7" reel

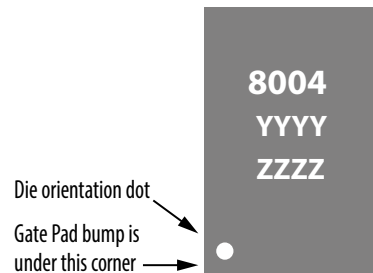


Die is placed into pocket solder bump side down (face side down)

Dimension (mm)	EPC8004 (note 1)		
	target	min	max
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (see note)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (see note)	2.00	1.95	2.05
g	1.5	1.5	1.6

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.  
 Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

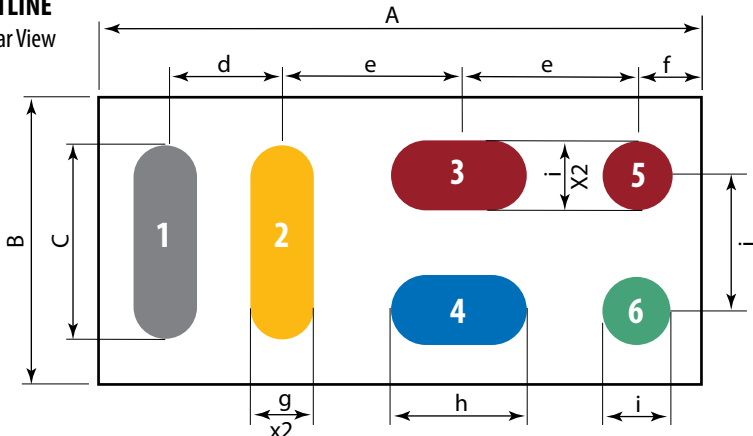
**DIE MARKINGS**



Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking Line 3
EPC8004	8004	YYYY	ZZZZ

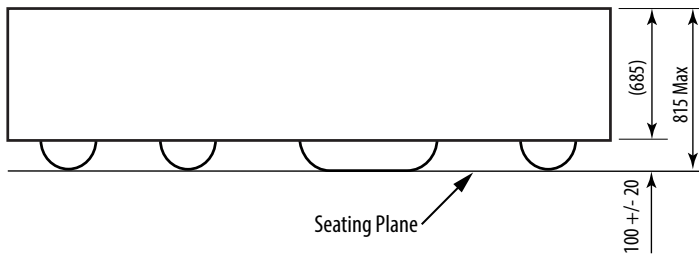
**DIE OUTLINE**

Solder Bar View



Dim	Micrometers		
	Min	Nominal	Max
A	2020	2050	2080
B	820	850	880
C	555	580	605
d	400	400	400
e	600	600	600
f	200	225	250
g	175	200	225
h	425	450	475
i	175	200	225
j	400	400	400

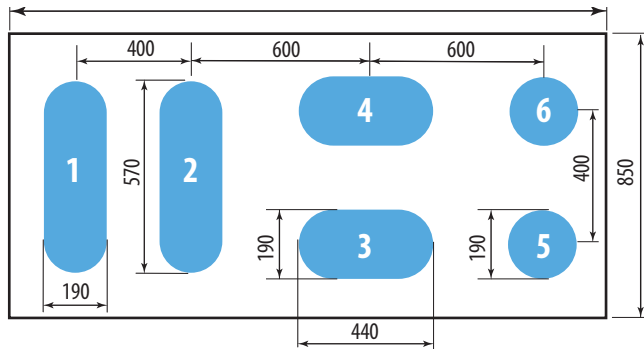
Side View



- Pad no. 1 is Gate
- Pad no. 2 is Source Return for Gate Driver
- Pad no. 3 and 5 are Source
- Pad no. 4 is Drain
- Pad no. 6 is Substrate\*

\*Substrate pin should be connected to Source

**RECOMMENDED LAND PATTERN** (measurements in  $\mu\text{m}$ )

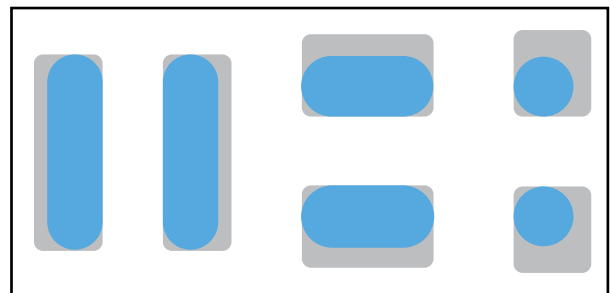
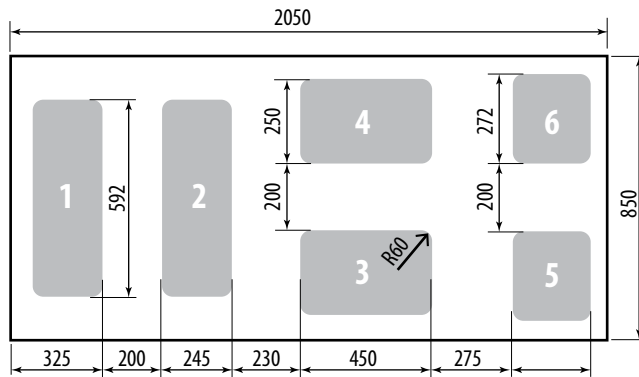


The land pattern is solder mask defined. Solder mask opening is 5  $\mu\text{m}$  smaller per side than bump.

- Pad no. 1 is Gate
- Pad no. 2 is Source Return for Gate Driver
- Pad no. 3 and 5 are Source
- Pad no. 4 is Drain
- Pad no. 6 is Substrate\*

\*Substrate pin should be connected to Source

**RECOMMENDED STENCIL DRAWING** (measurements in  $\mu\text{m}$ )



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, openings per drawing. Intended for use with SAC305 Type 3 solder, reference 88.5% metals content.

Additional assembly resources available at: <https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

Efficient Power Conversion Corporation (EPC) reserves the right to make changes without further notice to any products herein to improve reliability, function or design. EPC does not assume any liability arising out of the application or use of any product or circuit described herein; neither does it convey any license under its patent rights, nor the rights of others. eGaN® is a registered trademark of Efficient Power Conversion Corporation. EPC Patent Listing: [epc-co.com/epc/AboutEPC/Patents.aspx](http://epc-co.com/epc/AboutEPC/Patents.aspx)

Information subject to change without notice.

Revised August, 2019